

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	399	sram same (lic or local near interconnect or local near inter-connect)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/18 14:31
L2	31	sram same (lic or local near interconnect or local near inter-connect) near5 (groove or trench or via)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/18 14:31
L4	21	sram same (wiring or interconnect or interconnection or inter-connect or inter-connection or strap or trace) near4 (trench or groove or via) near4 (dielectric or ild or insulator or insulating)	US-PGPUB; USPAT	OR	ON	2005/03/18 15:01
S1	70338	(soi or box or buried near oxide) and (interconnect or interconnection or lic)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/18 08:44
S2	16820	(soi or box or buried near oxide) and (interconnect or interconnection or lic) and gate	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/19 11:35
S3	819	(soi or box or buried near oxide) and (interconnect or interconnection or lic) with gate with (active or semiconductor or silicon)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/19 11:39
S4	1852	(soi or box or buried near oxide) and (lic or local near interconnect or local near inter near connect or local near inter-connect)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/19 11:40
S5	603	(soi or box or buried near oxide) and (lic or local near interconnect or local near inter near connect or local near inter-connect) and gate and (source or drain or active)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/19 11:40
S6	298	(soi or box or buried near oxide) and (lic or local near interconnect or local near inter near connect or local near inter-connect) and gate and (source or drain or active) and sram	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/19 12:34
S7	97	(tft) and (lic or local near interconnect or local near inter near connect or local near inter-connect)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/19 13:28
S8	2	"6656806".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/01/19 13:28
S9	3	("5116771"   "5726100"   "6018180").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/01/19 13:28
S10	34	("5116771").URPN.	USPAT	OR	ON	2005/01/19 13:54
S11	336	438/164.ccls.	USPAT	OR	ON	2005/01/19 14:06
S12	1204	sram and soi	USPAT	OR	ON	2005/01/19 14:07
S13	831	sram and soi and (wiring or interconnect or inter-connect or interconnection or lic or interconnecting or trace)	USPAT	OR	ON	2005/01/19 14:07

S15	3185	(soi or box or buried near oxide) and (wiring or interconnection or interconnect or lic) near3 gate	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/15 08:45
S16	2082	(soi or box or buried near oxide or tft) and (wiring or interconnection or interconnect or lic) near3 gate near4 (source or drain or impurity or doped or active)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/15 08:46
S17	162	(soi or box or buried near oxide or tft) and (wiring or interconnection or interconnect or lic) near3 gate near4 (source or drain or impurity or doped or active) and (sram or sdram or dsram)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/15 13:26
S18	3	("5116771"   "5726100"   "6018180").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/03/15 11:19
S19	221	(soi or silicon adj on adj insulator) near6 (sram or sdram or dsram)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/15 13:27
S21	1451	(soi or box or buried near oxide or silicon adj on adj insulator) and (lic or local near interconnection or pt-lic or ft-lic)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 10:21
S22	12	(soi or box or buried near oxide or silicon adj on adj insulator) and (lic or local near interconnection or pt-lic or ft-lic) near5 (gate) near5 (source or drain or impurity or ldd) and (sdram or dsram or sram or dram)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 10:27
S23	14	(soi or box or buried near oxide or silicon adj on adj insulator) and (lic or local near interconnection or pt-lic or ft-lic) near5 (gate) near5 (source or drain or impurity or ldd)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 10:27
S24	111	(soi or box or buried near oxide or silicon adj on adj insulator) and (lic or local near interconnection or pt-lic or ft-lic) and (sram or sdram or dsram)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 10:38
S28	12	(US-20020020878-\$ or US-20030002321-\$ or US-20040241945-\$ or US-20040238892-\$ or US-20030127752-\$).did. or (US-5116771-\$ or US-5756394-\$ or US-5904512-\$ or US-6424011-\$ or US-6528853-\$ or US-6590800-\$ or US-6815282-\$).did.	US-PGPUB; USPAT	OR	ON	2005/03/17 11:43
S29	25	("4053335"   "4646271"   "4703456"   "4720323"   "4757360"   "4799194"   "4813018"   "5051958"   "5057448"   "5065201"   "5075888"   "5189641"   "5196722"   "5250827"   "5399516"   "5442210"   "5488579"   "5496756"   "5612238"   "5656537"   "5773152"   "5792681"   "5866451"   "5877525"   "5880991").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/03/17 11:50
S30	11	("6424011").URPN.	USPAT	OR	ON	2005/03/17 11:55
S31	231	(soi or box or buried near oxide or silicon adj on adj insulator) near5 (sram or dsram)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/17 15:39
S32	2	("5475244"   "5698869").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/03/17 16:22

S34	344	soi with sram	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/18 09:00
S35	11	(soi or silicon adj on adj insulator or box or buried adj oxide) same (field adj oxide or fox) same (sram or sdram or dsram or local near interconnection or lic or local near inter-connection or local near wiring or gate near2 (wiring or interconnect or interconnection or inter-connect) near2 (source or drain))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/18 10:43
S36	109	(soi or silicon adj on adj insulator or box or buried adj oxide) same (field adj oxide or fox) and (sram or sdram or dsram or local near interconnection or lic or local near inter-connection or local near wiring or gate near2 (wiring or interconnect or interconnection or inter-connect) near2 (source or drain or impurity))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/18 11:22
S37	17	(US-20020003241-\$ or US-20020020878-\$ or US-20030002321-\$ or US-20030127752-\$ or US-20040238892-\$ or US-20040241945-\$).did. or (US-5116771-\$ or US-5756394-\$ or US-5904512-\$ or US-6424011-\$ or US-6528853-\$ or US-6590800-\$ or US-6815282-\$ or US-6677642-\$ or US-6627952-\$ or US-6215155-\$ or US-5767549-\$).did.	US-PGPUB; USPAT	OR	ON	2005/03/18 15:00
S39	2255	(wiring or connection or trace or strap or interconnect or lic or ftlic or ptlic or inter-connect or interconnection or wire) near6 (trench or groove or embedded or embed or embedding) same (soi or tft or silicon adj on adj insulator or sos! or buried adj oxide or box)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/18 13:11
S40	24	(wiring or connection or trace or strap or interconnect or lic or ftlic or ptlic or inter-connect or interconnection or wire) near6 (trench or groove or embedded or embed or embedding) near15 (gate) same (soi or tft or silicon adj on adj insulator or sos! or buried adj oxide or box)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/18 14:30